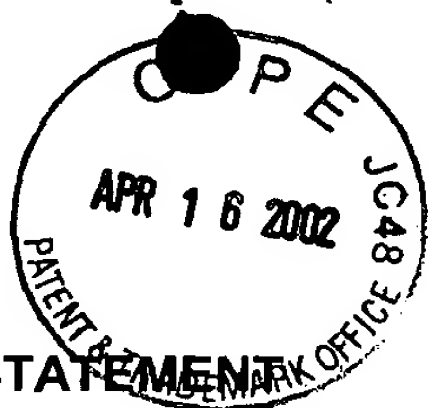


FORM PTO-1449 (modified)
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284105

P-0294.000-US

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: VAN SCHAIK et al

Application No.: 09/988,830

Filing Date: November 19, 2001

Examiner: Unknown

Group Art Unit: 4750-2851

Date: April 16, 2002

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HN	AR	6,252,648	06/2001	HASE et al.	355	53	
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284105

P-0294.000-US

Applicant: VAN SCHAIK et al

Application No.: 09/988,830

Filing Date: November 19, 2001

Examiner: Unknown

Group Art Unit: 2851

Date: September 13, 2002

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Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
HN	AR	6,411,368	06/2002	MATSUMOTO et al.	355	67	
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		Document Number	Date MM/YYYY	Country	Inventor Name		English Abstract		Translation Readily Available	
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HN	KR	0 660 188 A1	06/1995	EUROPE	STRAAIJER et al.					
	LR									
	MR									
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	OR									
	PR									
	QR									

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HN	RR	Bloomstein et al., "UV Cleaning of Contaminated 157-nm Reticles," <i>Proceedings of SPIE</i> 4346:669-375 (2001)							
	SR	Liberman, "Reticle Materials Testing Facilities at MIT Lincoln Laboratory," presented March 9, 2000							
	TR	Bloomstein et al., "UV Cleaning of Contaminated Reticles," presented August 1, 2000							
	UR	Bloomstein et al., "Studies of Laser Induced Contamination and Cleaning," presented November 21, 2000							
	VR	Bloomstein et al., "Optical Materials and Coatings at 157 nm," <i>Proceedings of SPIE</i> 3676:342-349 (1999)							
	WR	Bloomstein et al., "Laser Cleaning of Optical Elements in 157-nm Lithography," <i>Proceedings of SPIE</i> 4000:1537-1545 (2000)							
HN	XR	Bloomstein et al., "Controlled Contamination of Optics Under 157-nm Laser Irradiation," <i>Proceedings of SPIE</i> 4346:685-694 (2001)							

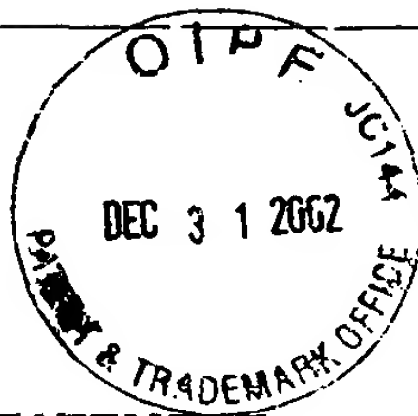
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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: VAN SCHAIK et al

Application No.: 09/988,830

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Date: December 31, 2002

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Examiner: Unknown

Group Art Unit: 2851

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Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
HN	AR	6,387,602	05/2002	HAYDEN et al.	430	327	
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